

MNDSPD.0005P



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Jones, et al. ) Group Art Unit: 2857  
App. No. : 09/810,932 )  
Filed : March 16, 2001 )  
For : **METHOD AND APPARATUS FOR** )  
**TRANSMISSION LINE ANALYSIS** )  
Examiner : Unknown )

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on

January 29, 2002  
*C. Miller*  
Chad W. Miller, Reg. No. 44,943

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:

Enclosed is form PTO-1449 listing references that are also enclosed. This Information Disclosure Statement is being filed before the mailing of the first Office Action on the merits, and as such, no fee is required in accordance with 37 C.F.R. § 1.97(b)(3).

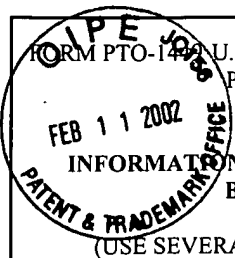
Dated: 1/29/02

Respectfully submitted,

By: *C. Miller*

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	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MNDSPD.0005P	APPLICATION NO. 09/810,932
	APPLICANT Jones, et al.		
	FILING DATE March 16, 2001	GROUP 2857	

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
JRW		Taylor, V. and Faulkner, M.; <u>Line Monitoring and Fault Location Using Spread Spectrum on Power Line Carrier</u> ; Published in IEE Proc.- Gener. Transm. Distrib., Vol. 143, No. 5, September 1996; Pages 427-434
JRW		Hwang, L., Rinne, G. and Turlik, I.; <u>An Extended Time-Domain Network Analysis Measurement Technique</u> ; Published in IEEE Transactions on Components, Packaging, and Manufacturing Technology, Part B, Vol. 18, No. 2, May 1995; Pages 375-380.
JRW		Dhaene, T., Martens, L. and Zutter, D.; <u>Calibration and Normalization of Time Domain Network Analyzer Measurements</u> ; Published in IEEE Transactions on Microwave Theory and Techniques, Vol. 42, No. 4, April 1994; Pages 580-589.

Cwm-1119.1

EXAMINER	<i>[Signature]</i>	DATE CONSIDERED	09/21/02
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\*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

FORM PTO-1449  
(MODIFIED)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MNDSPD.0005PAPPLICATION NO.  
09/810,932INFORMATION DISCLOSURE CITATION  
BY APPLICANTAPPLICANT(S)  
Jones, et al.FILING DATE  
March 16, 2001GROUP ART UNIT  
2857

(USE SEVERAL SHEETS IF NECESSARY)

EXAMINER  
INITIAL

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

JRW

Hayden, L. and Tripathi, V.; Calibration Methods for Time Domain Network Analysis; Published in IEEE Transactions on Microwave Theory and Techniques, Vol. 41, No. 3, March 1993; Pages 415-420

JRW

Su, W., and Riad, S.; Calibration of Time Domain Network Analyzers; Published in IEEE Transactions on Instrumentation and Measurement, Vol. 42, No. 2, April 1993; Pages 157-161.

JRW

Boets, P. and Van Biesen, L.; The Modelling Aspect of Transmission Line Networks; 1992; Pages 137-141.

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Munk, A. and Cusick, J.; A Time Domain Analysis of a Calibration Error Model; 1991; Pages 22-26.

JRW

Pintelon, R., and Van Biesen, L.; Identification of Transfer Functions With Time Delay and Its Application to Cable Fault Location; Published in IEEE Transactions on Instrumentation and Measurement, Vol. 39, No. 3, June 1990; Pages 479-484.

JRW

Van Biesen, L., Renneboog, J. and Barel, A.; High Accuracy Location of Faults on Electrical Lines Using Digital Signal Processing; Published in IEEE Transactions on Instrumentation and Measurement, Vol. 39, No. 1, February 1990; Pages 175-179.

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